

DOCUMENT CHANGE REQUEST

421 DCR number Changes required for: N/A Originator: aissa nehdi Date: 2008/07/24 Date sent: 2008/07/24 Organisation: CNES Status: IMPLEMENTED Title: Transistors Low Power NPN, based on type 2N2222A 2 Number: 5201/002 Issue: Other documents affected: Page: 1.4.2 Component Type Variants page 5 1.6 PHYSICAL DIMENSIONS AND TERMINAL IDENTIFICATION page 6 Paragraph: 1.4.2 Component Type Variants page 5 1.6 PHYSICAL DIMENSIONS AND TERMINAL IDENTIFICATION page 6 Original wording: Proposed wording: Variants 11 & 12 added (Chip Carrier Package CCP) 3 terminal Justification: NA Attachments: dcr421att08_09_19.pdf, DCR421att.pdf, null Modifications: In order to incorporate the 2 new Variants, 11 & 12, the changes as shown in the modified attachment (see attached), shall be made to Paras 1.4.2, 1.5, 1.6.3 (new para), 1.7, 2.4.1 of 5201/002 issue 2. see attached Approval signature: Date signed: 2008-07-24

MODIFIED ATTACHMENT FOR DCR421 SLIDWING APPROVED WORDING IF DIFFERENT FROM "PROPOSED WORDING":

1919/08

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1.4.2 Component Type Variants
The component type variants applicable to this specification are as follows:

Variant		T /	Lead/Terminal	Weight
Number	Based on Type	Case	Material and finish	max g
01	2N3700	TO-18	D2/	0.4
02	2N3700	TO-18	D3 ør D4	0.4
04	2N3700	ССР	/ 2	0.06
05	2×3700	ССР	4	0.06
06	2N3700	CCP	2	0.06
07	2N3700	CCP	<u>å</u>	0.06

See marking of Para 1.4.2 attached: *

1.5 Maximum Rating See mark-p of Para 1.5 attached ** (VCEO)

1.7 Functional Diagram
Lee made-up of Para 1.7 attached: *

2.4.1 Room Temp Electrical Measurement For V(BR)CED see making of Table attached: * For Ihrel —#—



1. **GENERAL**

1.1 SCOPE

This specification details the ratings, physical and electrical characteristics and test and inspection data for the component type variants and/or the range of components specified below. It supplements the requirements of, and shall be read in conjunction with, the ESCC Generic Specification listed under Applicable Documents.

1.2 <u>APPLICABLE DOCUMENTS</u>

The following documents form part of this specification and shall be read in conjunction with it:

- (a) ESCC Generic Specification No. 5000
- (b) MIL-STD-750, Test Methods and Procedures for Semiconductor Devices

1.3 TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESCC Basic Specification No. 21300 shall apply.

1.4 THE ESCC COMPONENT NUMBER AND COMPONENT TYPE VARIANTS

1.4.1 The ESCC Component Number

The ESCC Component Number shall be constituted as follows:

Example: 520100201

- Detail Specification Reference: 5201002
- Component Type Variant Number: 01 (as required)

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1.4.2 <u>Component Type Variants</u>

The component type variants applicable to this specification are as follows:

	(3Terminal)								
Variant Number	Based on Type	Case	Lead/Terminal Material and/or Finish	Weight max g	V _{(BR)CEO} min V	lh _{fe} l			
01	2N2222A	TO-18	D2	0.4	40	3 to 10			
02	2N2222A	TO-18	D3 or D4	0.4	40	3 to 10			
04	2N2222A	CCP	2	0.06	40	3 to 10			
05	2N2222A	CCP	4	0.06	40	3 to 10			
06	2N2222A	TO-18	D2	0.4	50	2.5 min			
07	2N2222A	TO-18	D3 or D4	0.4	50	2.5 min			
09	2N2222A	CCP 🖟	2	0.06	50	2.5 min			
10	2N2222A	CCP 🗷	4	0.06	50	2.5 min			

The lead/terminal material and/or finish shall be in accordance with the requirements of ESCC Basic Specification No. 23500.

,	11	2N2222A	CCP CHTERMINA	2	0.06	L+C	3410	The same and a same a s
	12	2N2222A	CCP (4Terminul)	Lþ	0.06	40	3610	



1.5 **MAXIMUM RATINGS**

The maximum ratings shall not be exceeded at any time during use or storage.

Maximum ratings shall only be exceeded during testing to the extent specified in this specification and when stipulated in Test Methods and Procedures of the ESCC Generic Specification.

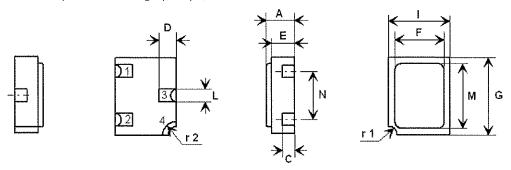
Characteristics	Symbols	Maximum Ratings	Unit	Remarks
Collector-Base Voltage	V _{CBO}	75	V	Over entire
Collector-Emitter Voltage	V _{CEO}		٧	operating temperature
Variants 01 to 05, 11, 12		40		range
Variants 06 to 10		50		
Emitter-Base Voltage	V _{EBO}	6	٧	
Collector Current	I _C	800	mA	Continuous
Power Dissipation For TO-18 and CCP	P _{tot1}	0.5	w	At T _{amb} ≤ +25°C Note 1
For CCP	P _{tot2}	0.73 (Note 2)	W	
For TO-18	P _{tot3}	1.8	W	At T _{case} ≤ +25°C Note 1
Operating Temperature Range	T _{op}	-65 to +200	°C	Note 3
Storage Temperature Range	T _{stg}	-65 to +200	°С	Note 3
Soldering Temperature For TO-18 For CCP	T _{sol}	+260 +245	°C	Note 4 Note 5

NOTES:

- For T_{amb} or $T_{case} > +25^{\circ}C$, derate linearly to 0W at +200°C. When mounted on a 15 x 15 x 0.6mm ceramic substrate.
- For Variants with tin-lead plating or hot solder dip lead finish all testing performed at $T_{amb} > +125^{\circ}C$ shall be carried out in a 100% inert atmosphere.
- Duration 10 seconds maximum at a distance of not less than 1.5mm from the device body and the same lead shall not be resoldered until 3 minutes have elapsed.
- Duration 5 seconds maximum and the same terminal shall not be resoldered until 3 minutes have elapsed.



1.6.3 Chip Carrier Package (CCP) - 3 terminal



	Dimens	Dimensions mm		
Symbols	Min	Max	Notes	
А	1.15	1.5		
С	0.45	0.56	2	
D	0.6	0.91	2	
E	0.91	1.12		
F	1.9	2.15		
G	2.9	3.25		
I	2.4	2.85		
L	0.4	0.6	2	
М	2.4	2.65		
N	1.8	2		
r1	0.3 יד	0.3 TYPICAL		
r2	0.56 T	1		

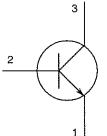
- NOTES:

 1. Terminal identification is specified by reference to the corner notch position where terminal 1 = emitter, terminal 2 = base, terminal 3 = collector, terminal 4 = \$hielding connected to the lid.

 2. Applies to ## terminals, 1, 2, 3



1.7 **FUNCTIONAL DIAGRAM**



- 1. Emitter.
- Base.
- 3. Collector.
- 4. Shielding

(Variants 04,05,09,11)

- For TO-18, the collector is internally connected to the case. For CCP the lid is not connected to any terminal.
- 3. For 4 Kenninal CCP (Varianto 11,12), the shielding terminal is connected to the lid.

1.8 MATERIALS AND FINISHES

Materials and finishes shall be as follows:

- Case
 - For the metal can package the case shall be hermetically sealed and have a metal body with hard
 - For the chip carrier package the case shall be hermetically sealed and have a ceramic body with a Kovar lid.
- b) Leads/Terminals

As specified in Component Type Variants.

2. REQUIREMENTS

2.1 **GENERAL**

The complete requirements for procurement of the components specified herein are as stated in this specification and the ESCC Generic Specification. Permitted deviations from the Generic Specification, applicable to this specification only, are listed below.

Permitted deviations from the Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESCC requirement and do not affect the component's reliability, are listed in the appendices attached to this specification.

2.1.1 **Deviations from the Generic Specification**

(a) Deviation from Screening Tests - Chart F3 High Temperature Reverse Bias Burn-in and the subsequent Final Measurements for HTRB shall be omitted.

2.2 MARKING

The marking shall be in accordance with the requirements of ESCC Basic Specification No. 21700 and

The information to be marked on the component shall be:

(a) The ESCC qualified components symbol (for ESCC qualified components only).



- (b) The ESCC Component Number.
- (c) Traceability information.

2.3 <u>TERMINAL STRENGTH</u>

The test conditions for terminal strength, tested as specified in the ESCC Generic Specification, shall be as follows:

For TO-18, Test Condition: E, lead fatigue.

2.4 <u>ELECTRICAL MEASUREMENTS AT ROOM, HIGH AND LOW TEMPERATURES</u>

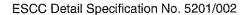
Electrical measurements shall be performed at room, high and low temperatures.

2.4.1 Room Temperature Electrical Measurements

The measurements shall be performed at T_{amb} =+22 ±3°C.

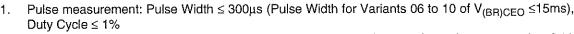
Characteristics	Symbols	MIL-STD-750	Test Conditions	Lir	nits	Units
		Test Method		Min	Max	
Collector-Base Breakdown Voltage	V _{(BR)CBO}	3001	I _C = 100μA Bias Condition D	75	-	V
Collector-Emitter Breakdown Voltage Variants 01 to 05,1 Variants 06 to 10	V _{(BR)CEO}	3011	Bias Condition D Note 1 I _C = 30mA I _C = 10mA	40 50	-	V
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	3026	I _E = 100μA Bias Condition D	6	-	V
Collector-Base Cut-off Current	Ісво	3036	V _{CB} = 60V Bias Condition D	B.	10	nA
Emitter-Base Cut- off Current	I _{EBO}	3061	V _{EB} = 3V Bias Condition D	-	10	nA
Collector-Emitter Saturation Voltage	V _{CE(sat)}	3071	I _C =150mA, I _B =15mA Note 1	-	300	mV
Base-Emitter Saturation Voltage	V _{BE(sat)}	3066	I _C =150mA, I _B =15mA Note 1	au	1.2	V
Forward-Current	h _{FE1}	3076	$V_{CE}=10V, I_{C}=100\mu A$	35	-	-
Transfer Ratio	h _{FE2}		V _{CE} =10V, I _C = 10mA	75	-	-
	h _{FE3}		V_{CE} =10V, I_{C} = 150mA Note 1	100	300	-
	h _{FE4}		V _{CE} =10V, I _C = 500mA Note 1	40	-	*







Characteristics	Symbols	MIL-STD-750	Test Conditions	Lin	nits	Units
	Test Method		Min	Max		
Small-Signal Forward-Current Transfer Ratio	lh _{fe} l	3306	V _{CE} =20V, I _C =20mA f=100MHz Note 2			-
Variants 01 to 05,	11,12			3	10	
Variants 06 to 10				2.5	-	
Output Capacitance	C _{obo}	3236	V _{CB} =10V, I _E =0A 100kHz≤f≤1MHz Note 2	-	8	pF
Turn-on Time	t _{on}	-	I _C =150mA I _B =15mA Notes 2, 3	-	35	ns
Turn-off Time	t _{off}	•	I _C =150mA I _B =15mA Notes 2, 4	-	285	ns



For AC characteristics read and record measurements shall be performed on a sample of 32 components with 0 failures allowed. Alternatively a 100% inspection may be performed.

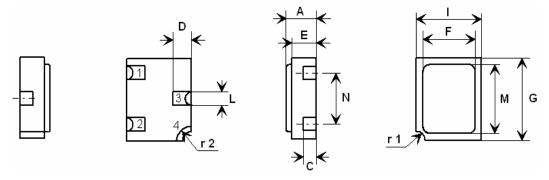


^{3.} t_{on} shall be measured using the following test circuit. The input waveform shall be supplied by a pulse generator with the following characteristics: $Z_{OUT} = 50\Omega$, $t_r \le 2$ ns, Pulse Width = 200 ± 1 0ns, Duty Cycle ≤ 2 %. The input and output waveforms shall be monitored on an oscilloscope with the following: $Z_{IN} \ge 100 k\Omega$, input capacitance ≤ 12 pF, $t_r \le 5$ ns.

1.4.2 Component Type Variants
The component type variants applicable to this specification are as follows:

Variant Number	Based on Type	Case	Lead/Terminal Material and finish	Weight max g
01	2N3700	TO-18	D2	0.4
02	2N3700	TO-18	D3 or D4	0.4
04	2N3700	ССР	2	0.06
05	2N3700	ССР	4	0.06
06	2N3700	CCP	2	0.06
07	2N3700	CCP	4	0.06

1.6.3 Chip Carrier Package (CCP) - 3 terminal



O verk ele	Dimensi	ions mm	Nata
Symbols	Min	Max	Notes
А	1.15	1.5	
С	0.45	0.56	2
D	0.6	0.91	2
E	0.91	1.12	
F	1.9	2.15	
G	2.9	3.25	
I	2.4	2.85	
L	0.4	0.6	2
М	2.4	2.65	
N	1.8	2	
r1	0.3 TY	1	
r2	0.56 TYPICAL		

NOTES:

- Terminal identification is specified by reference to the corner notch position where terminal 1 = emitter, terminal 2 = base, terminal 3 = collector, terminal 4 = Shielding connected to the lid.
 Applies to all terminals.